

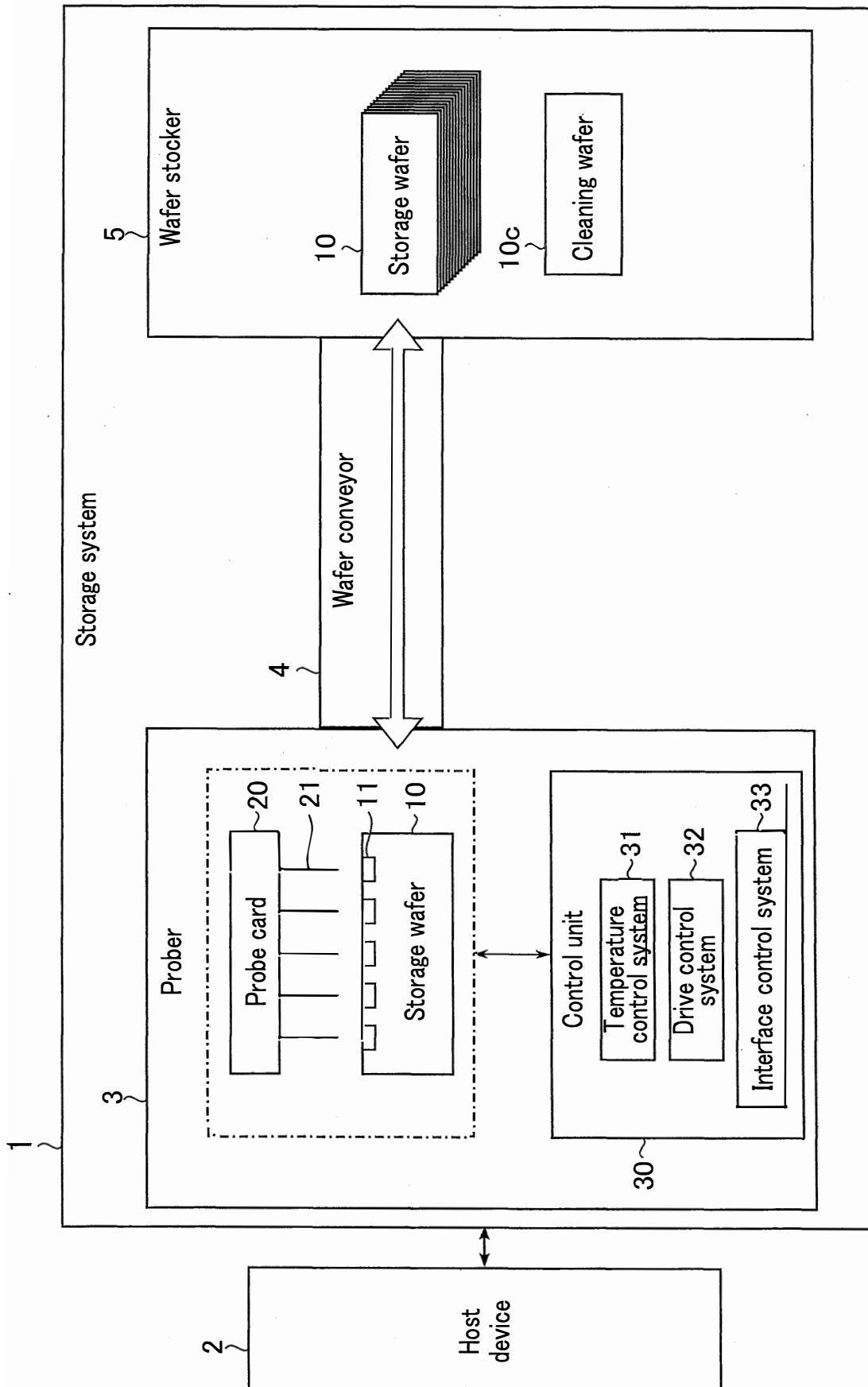


FIG. 1

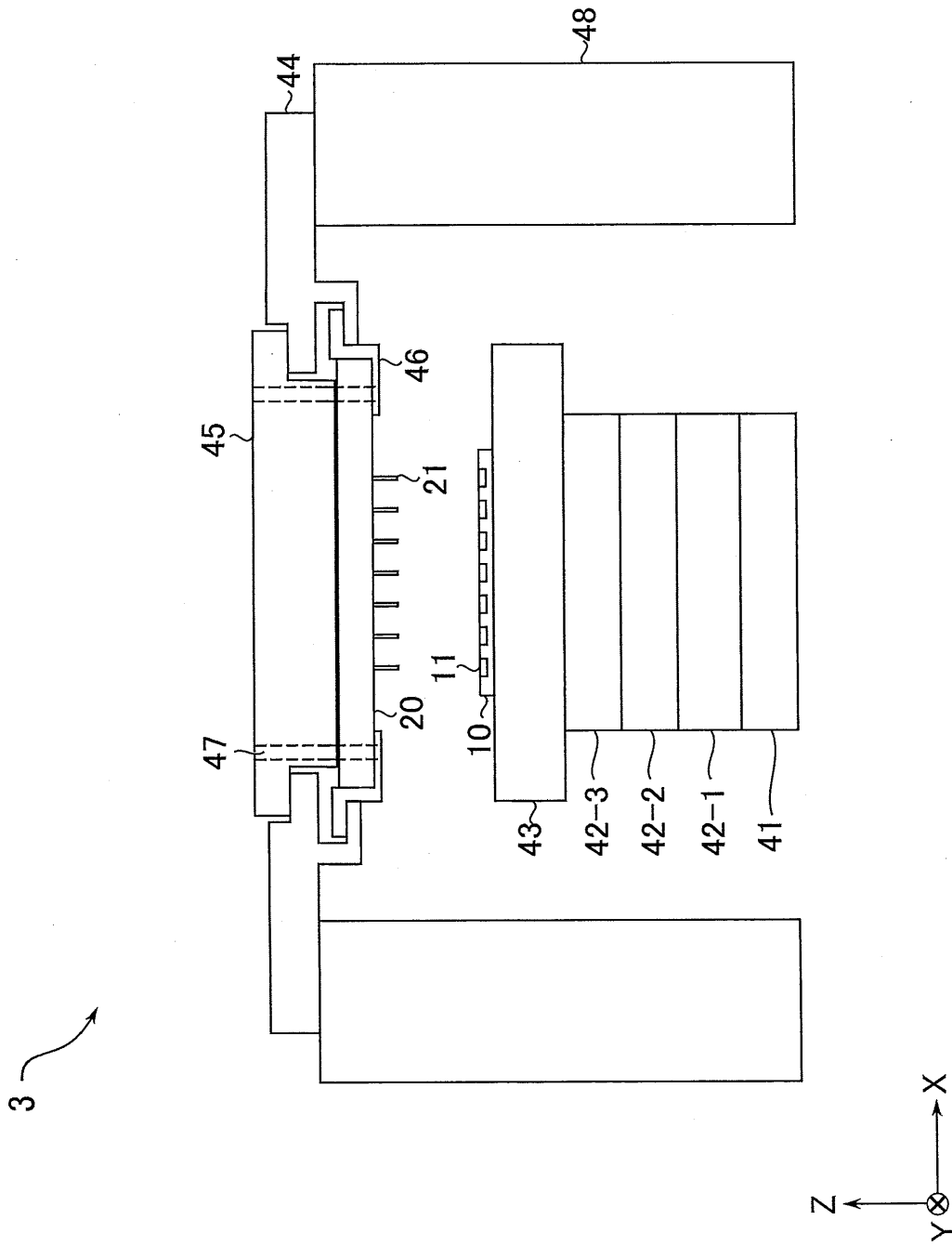


FIG. 2

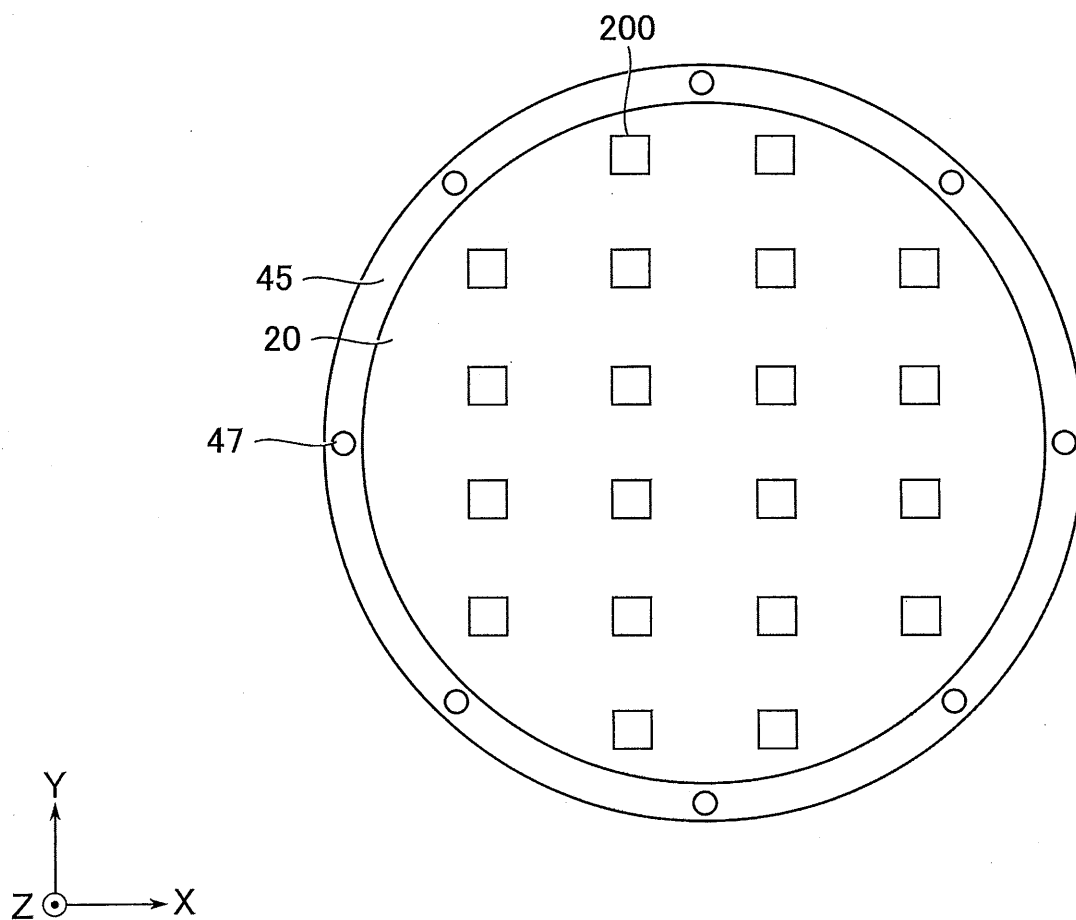


FIG. 3

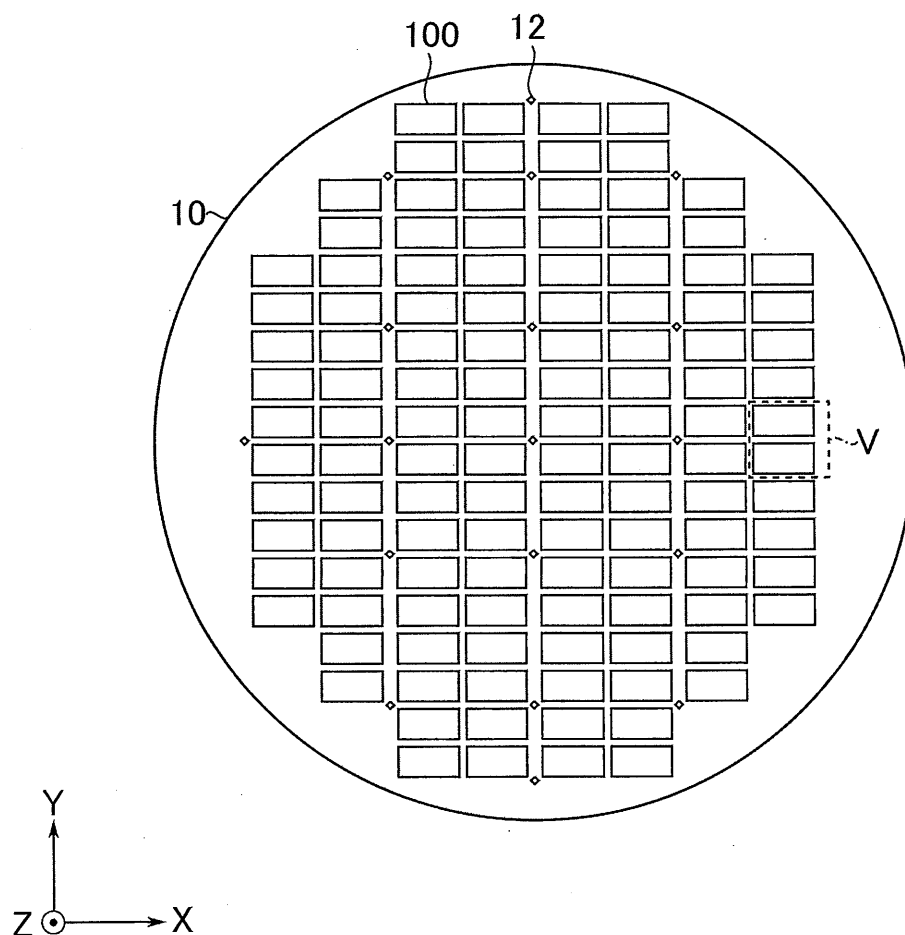


FIG. 4

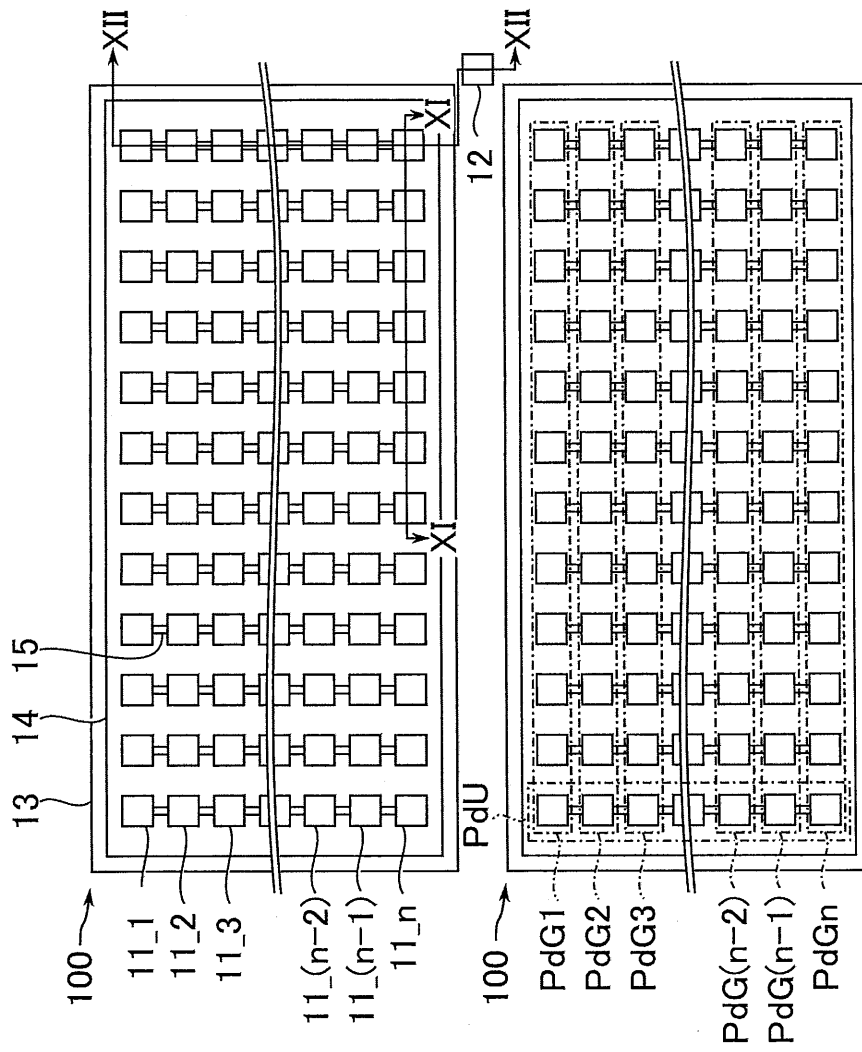


FIG. 5

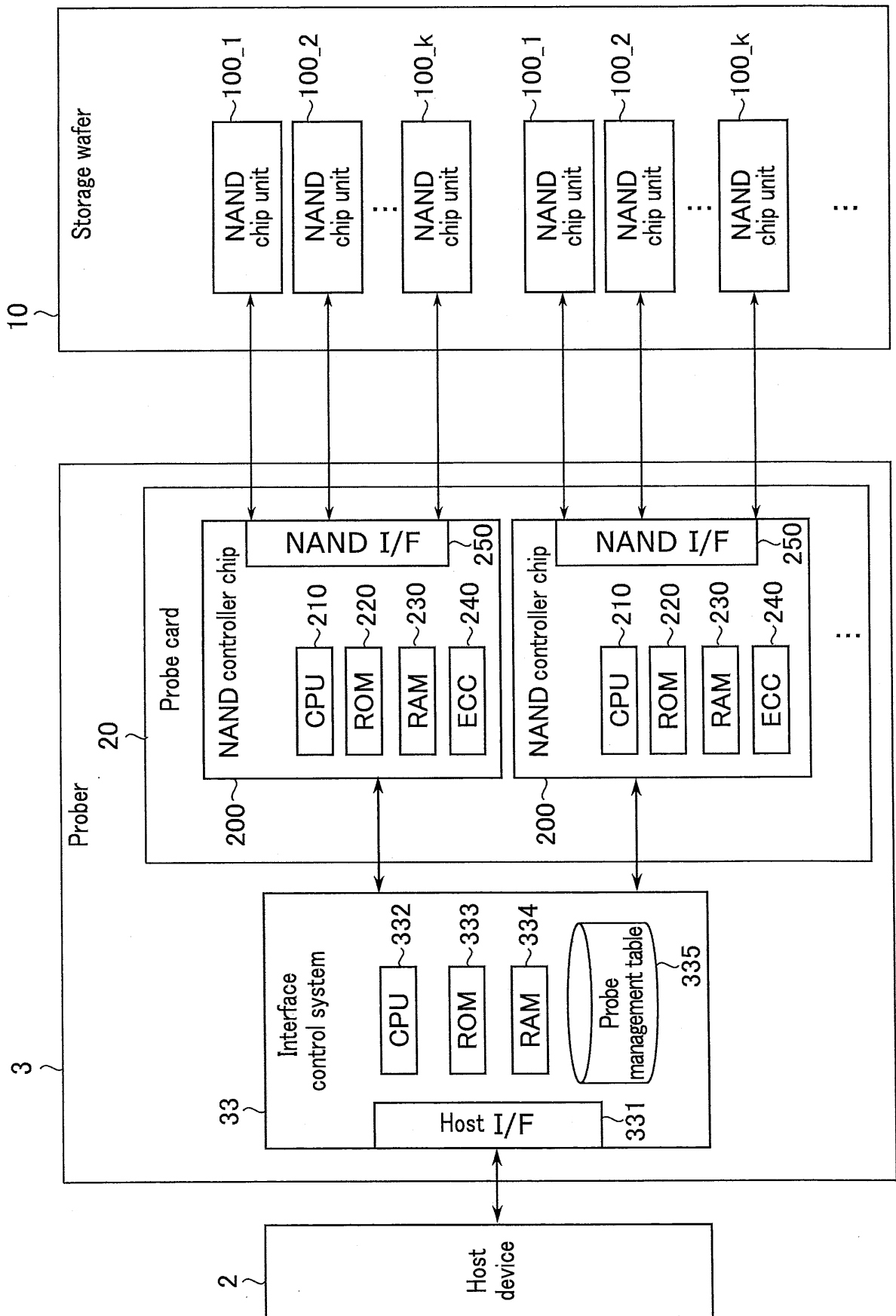


FIG. 6

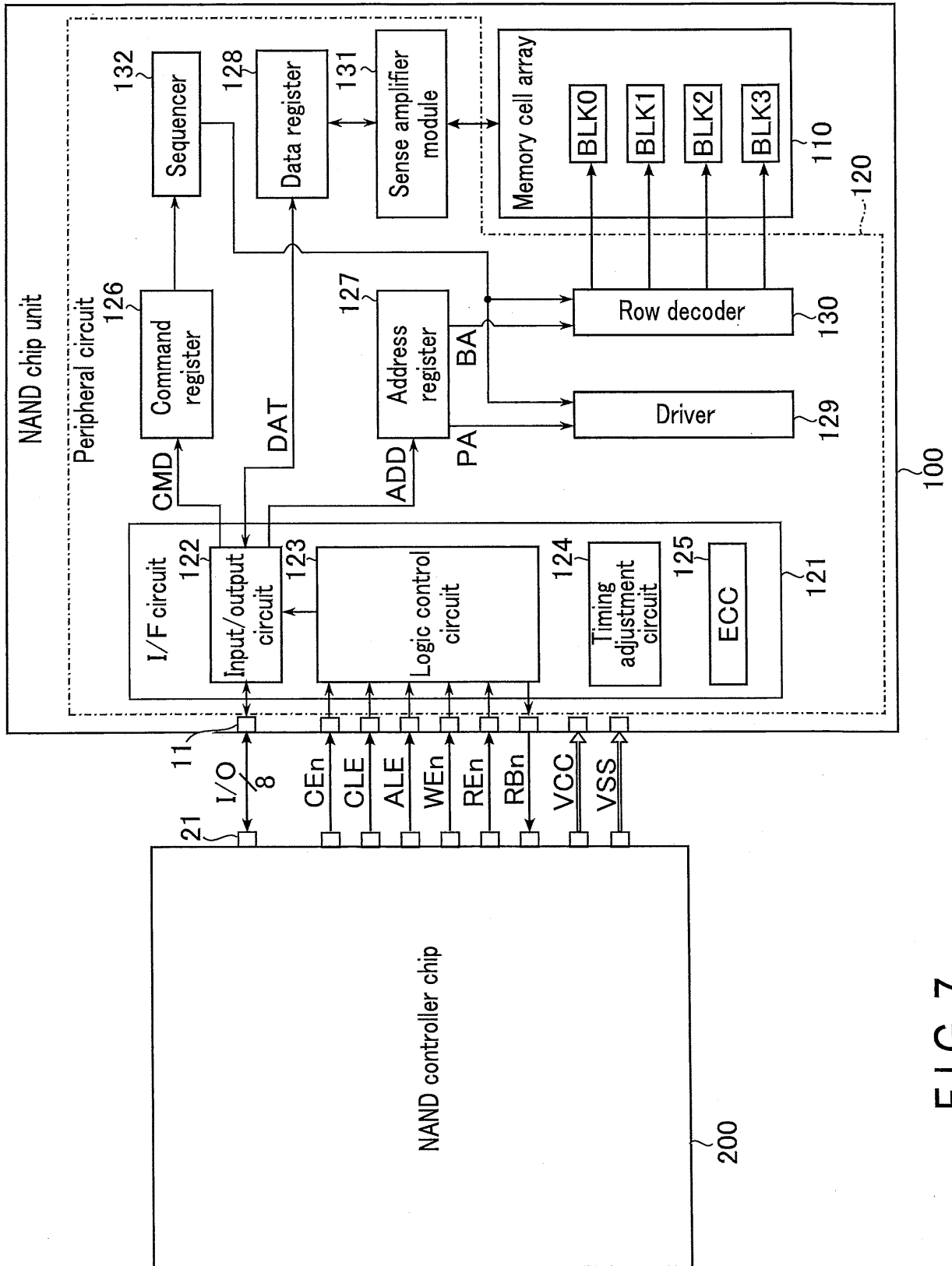
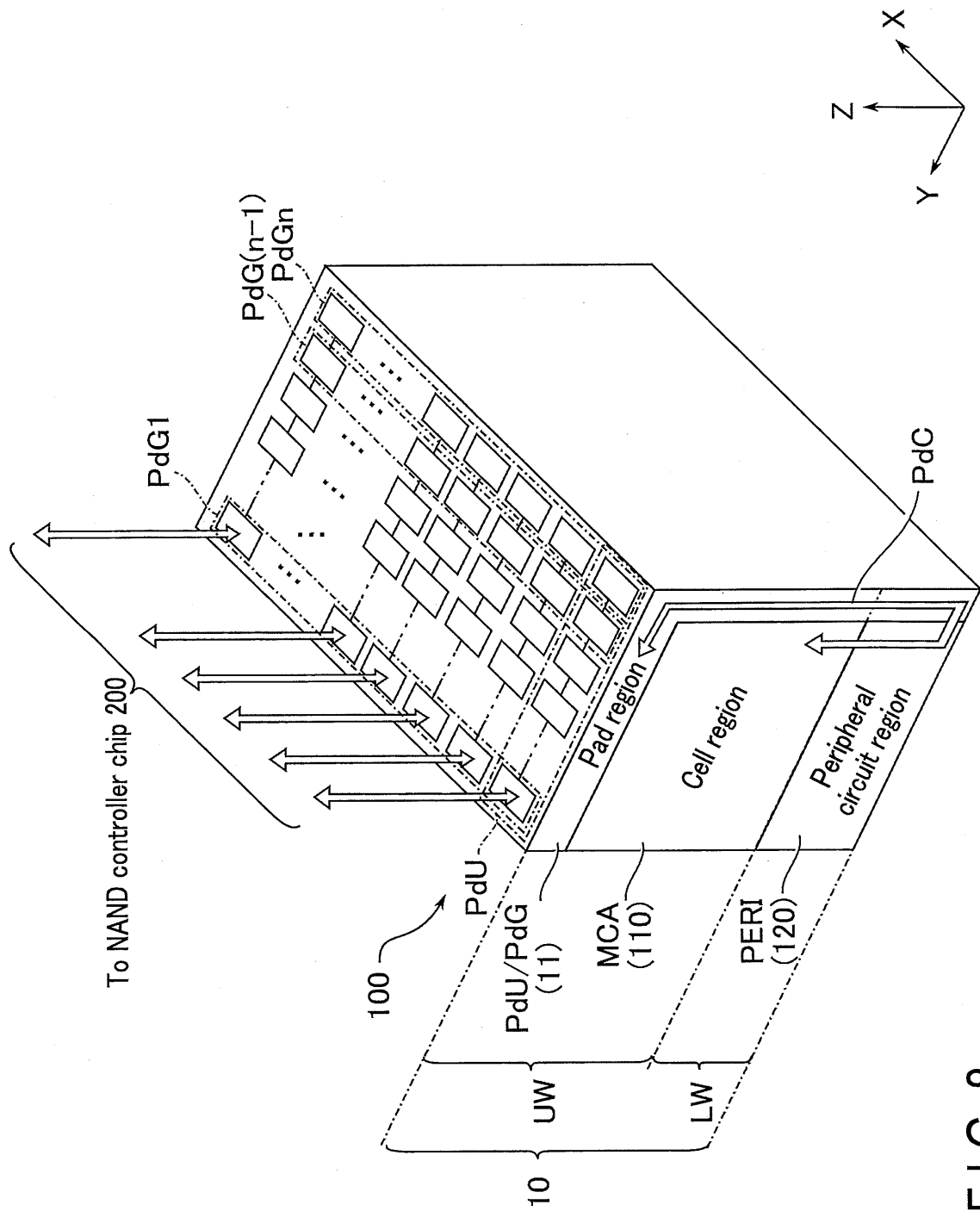


FIG. 7



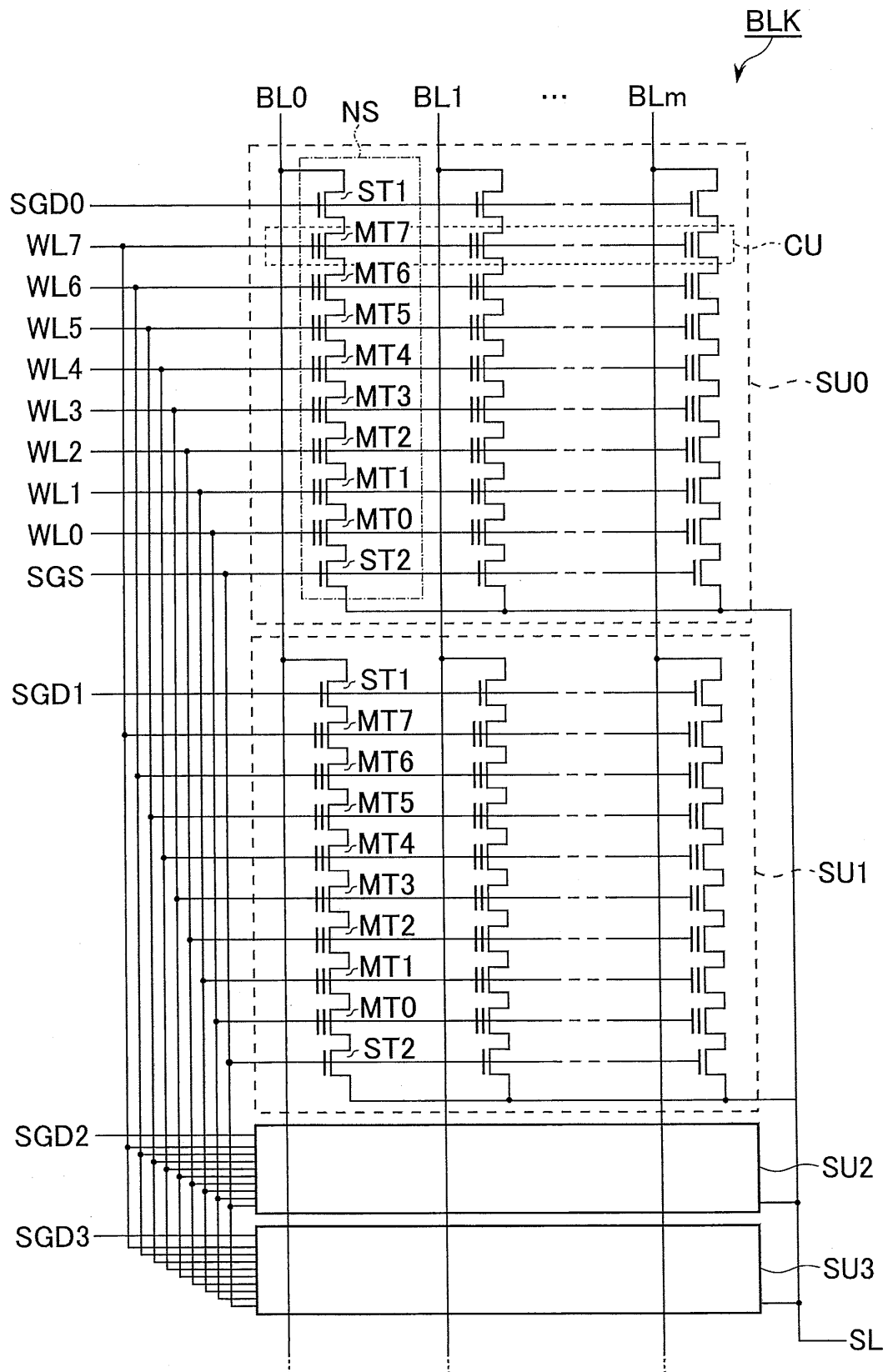


FIG. 9

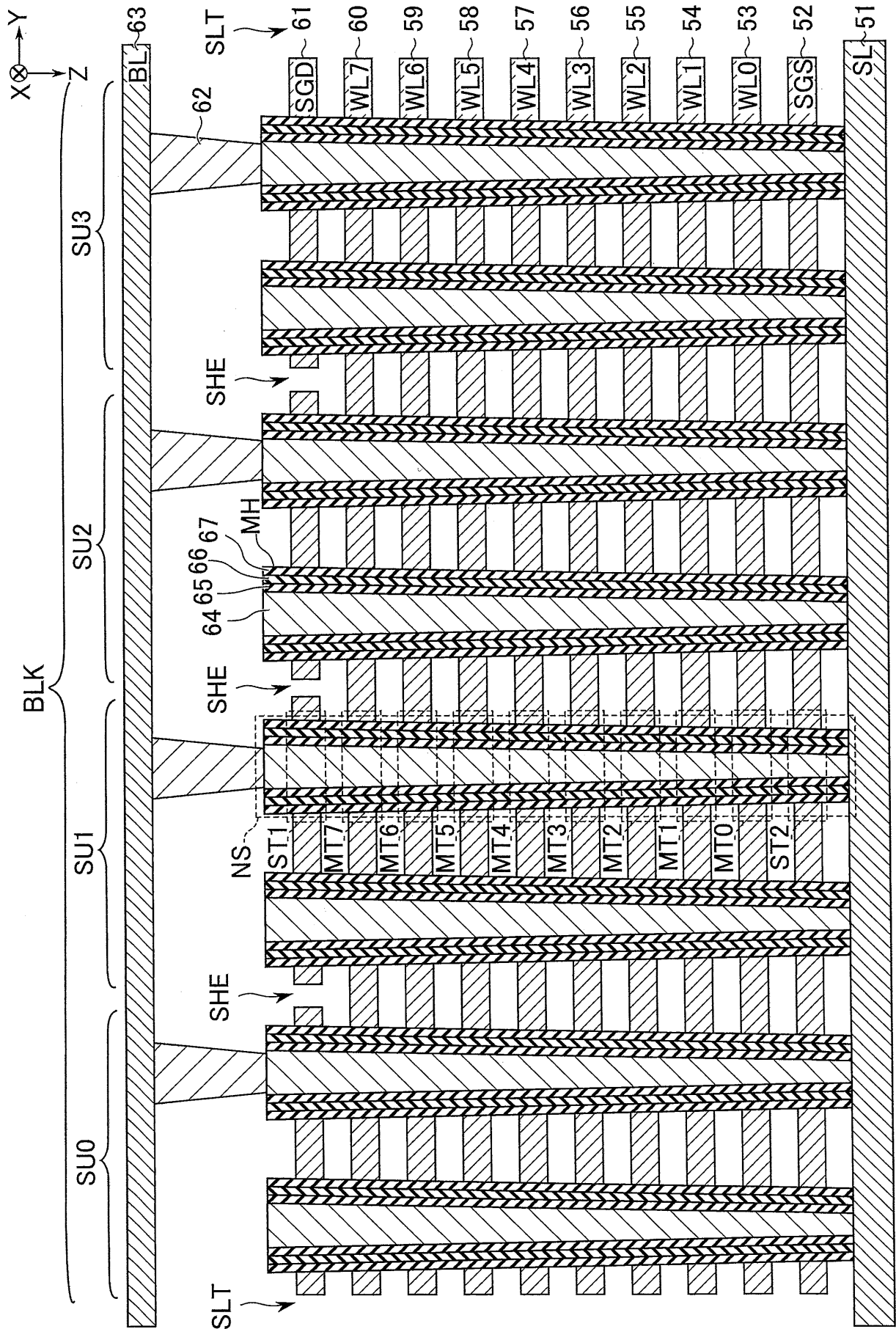


FIG. 10

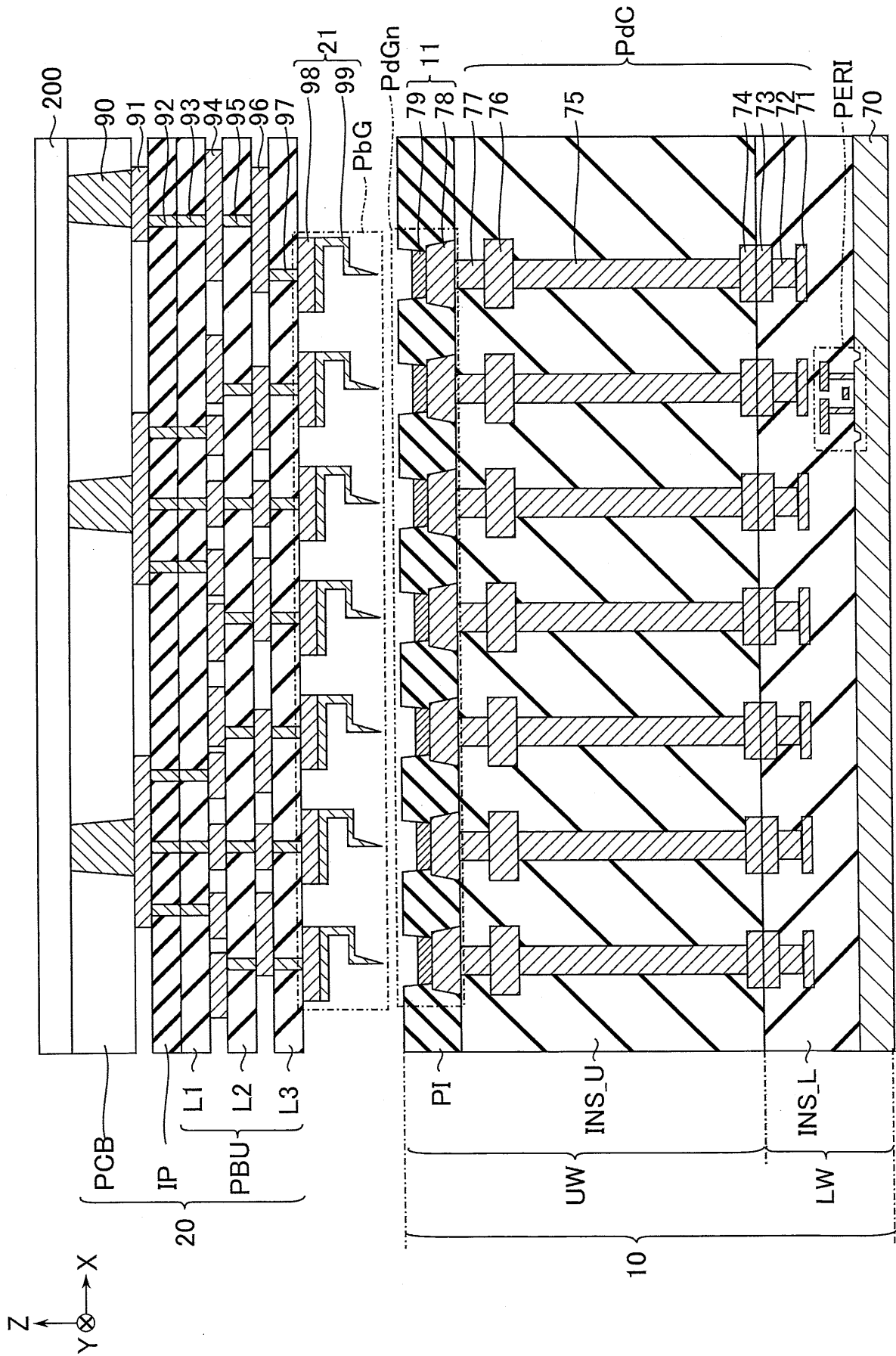


FIG. 11

335

Type			Number of probing	Defect flag
Wafer or card		Pad group		
Storage wafer	W1	PdG1	10	True
		PdG2	8	True
		PdG3	3	False
		⋮	⋮	⋮
		PdGn	0	False
	W2	PdG1	9	True
		PdG2	1	False
		PdG3	0	False
		⋮	⋮	⋮
		PdGn	0	False
	⋮	⋮	⋮	⋮
Probe card			31	

FIG. 13

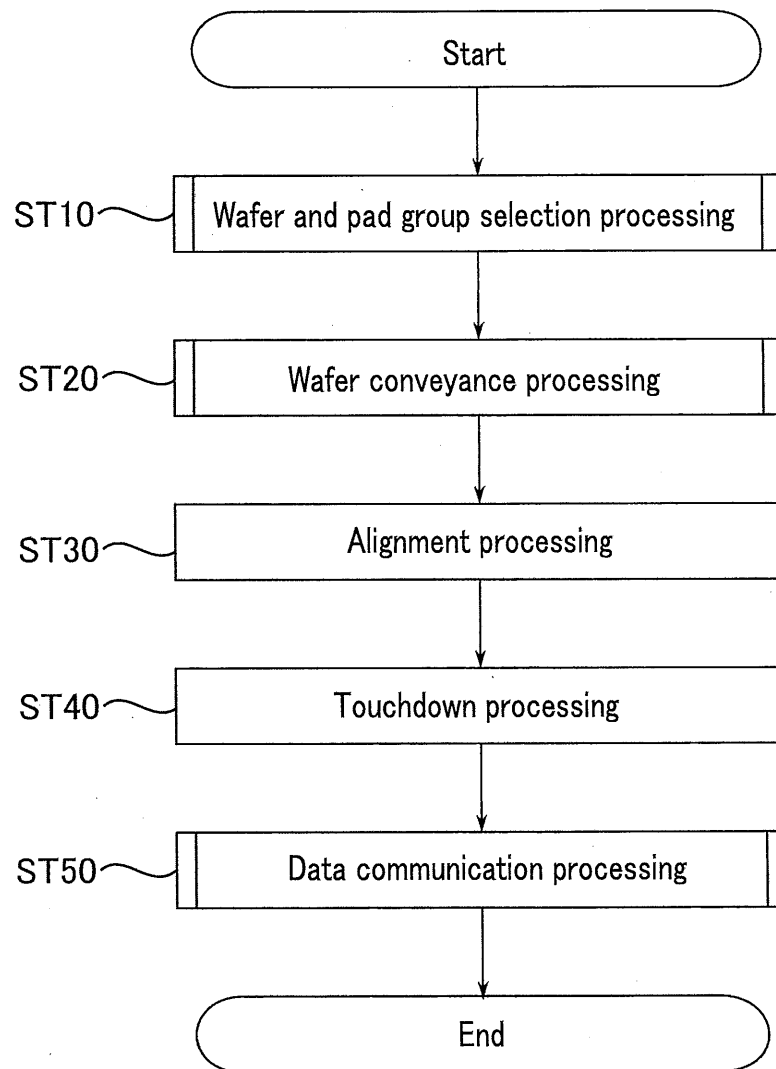


FIG. 14

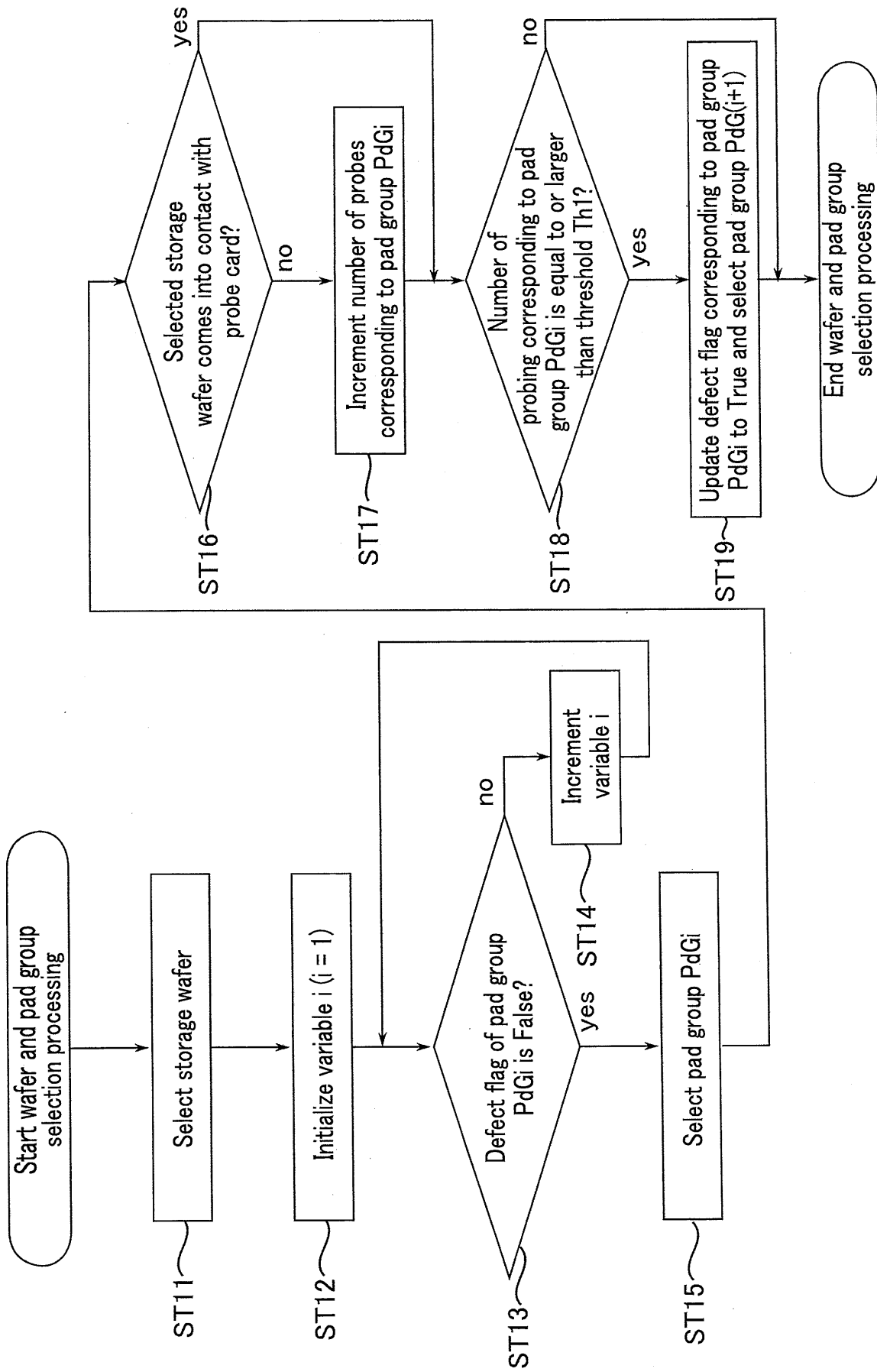


FIG. 15

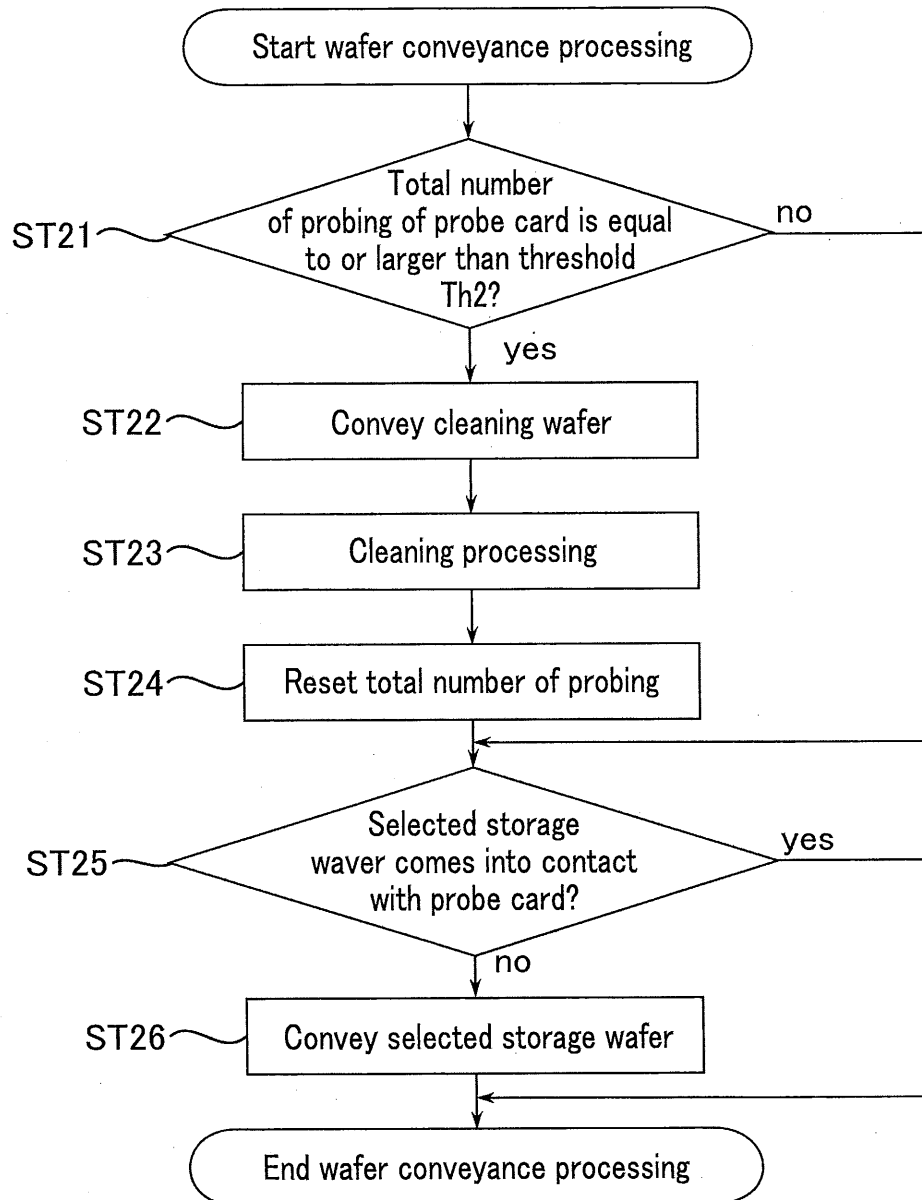


FIG. 16

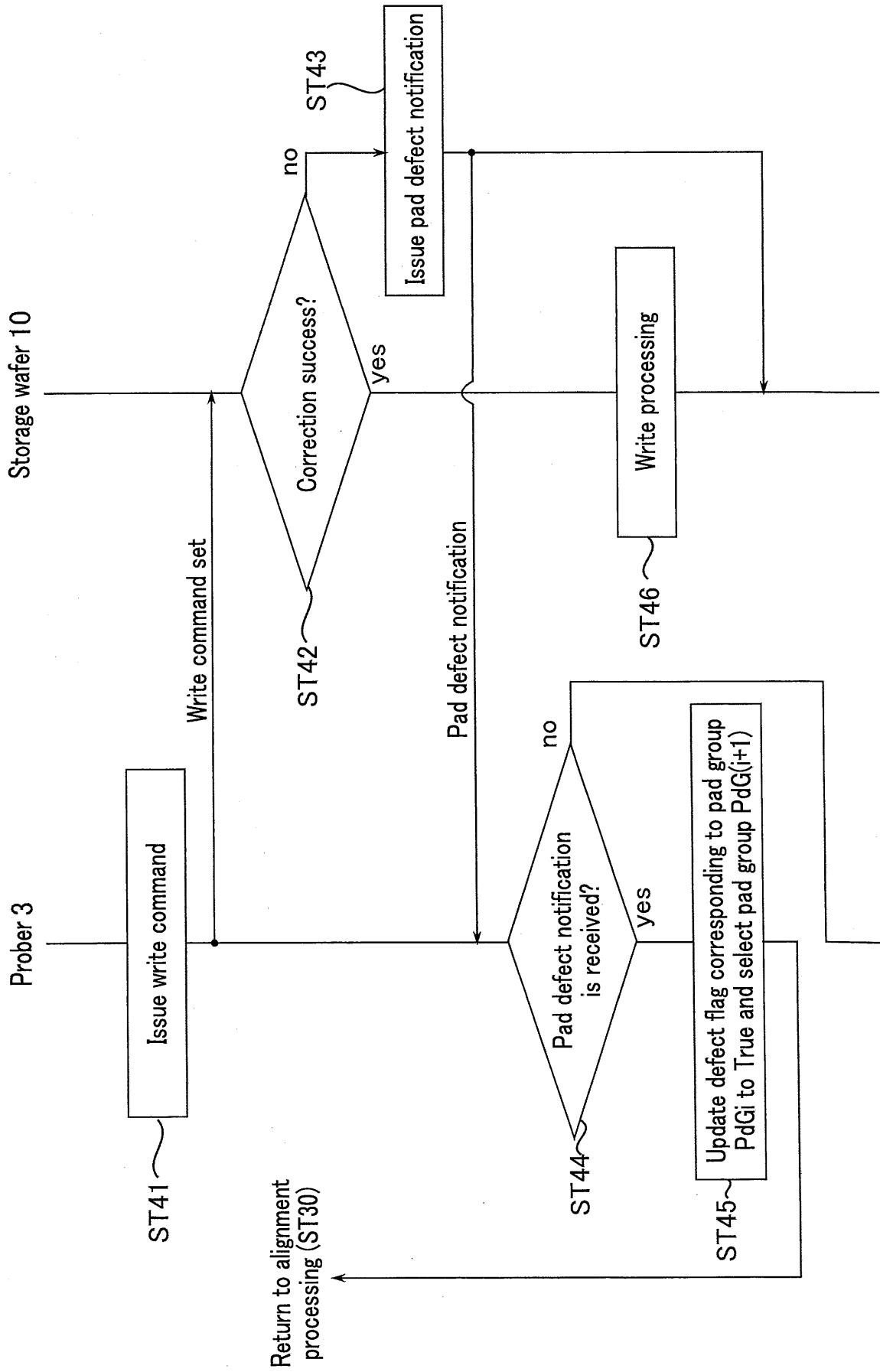


FIG. 17

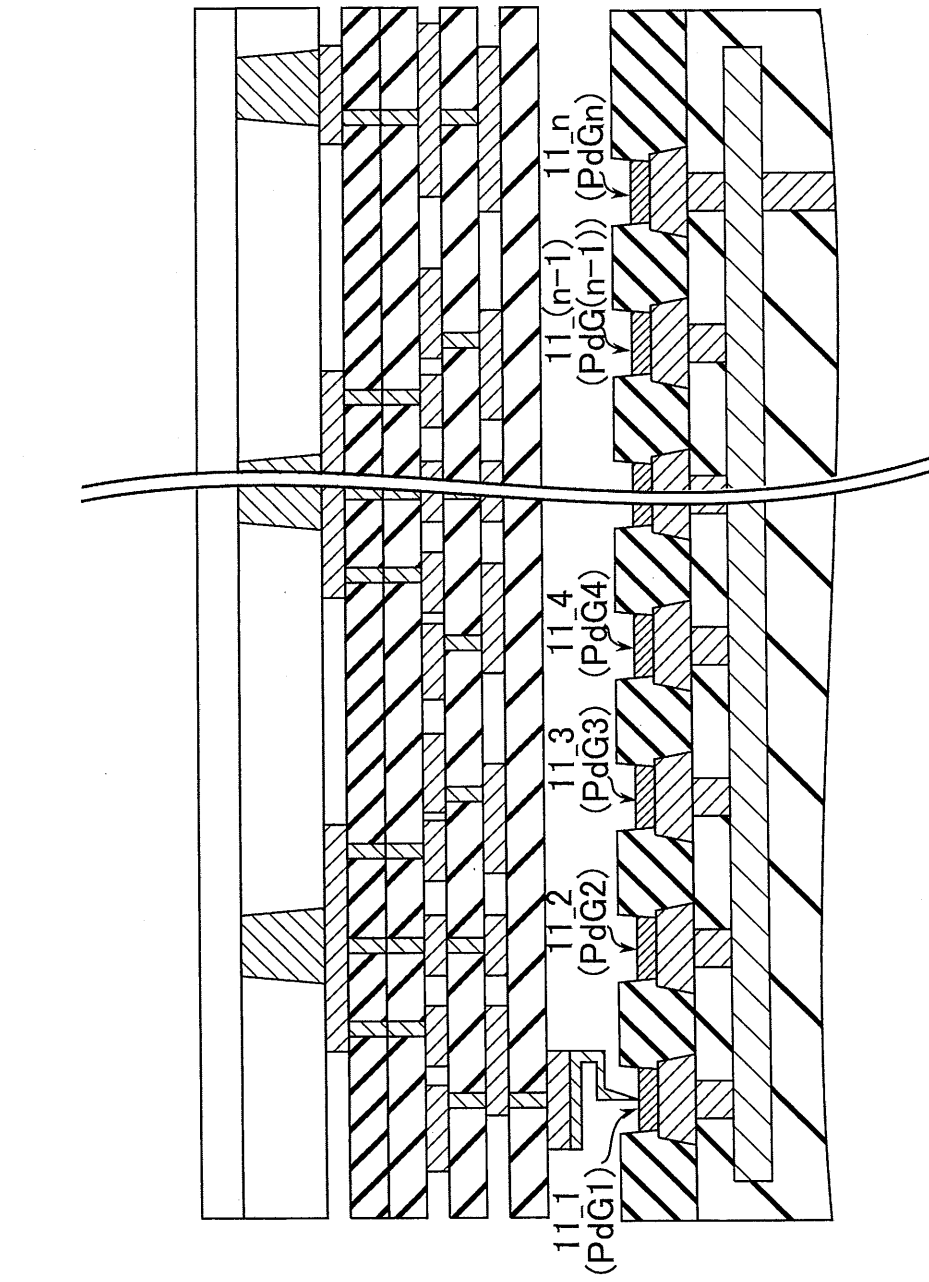


FIG. 18

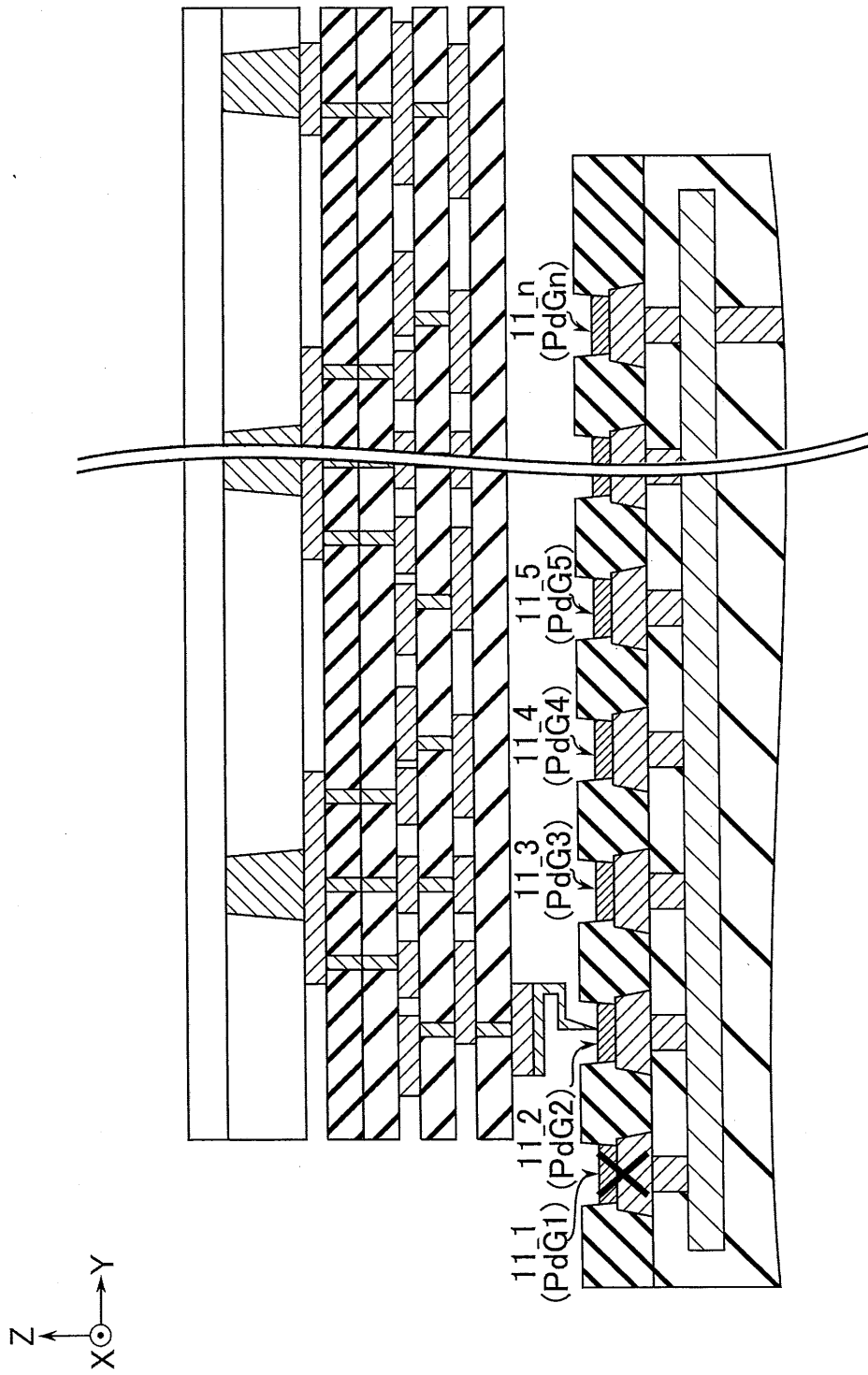


FIG. 19

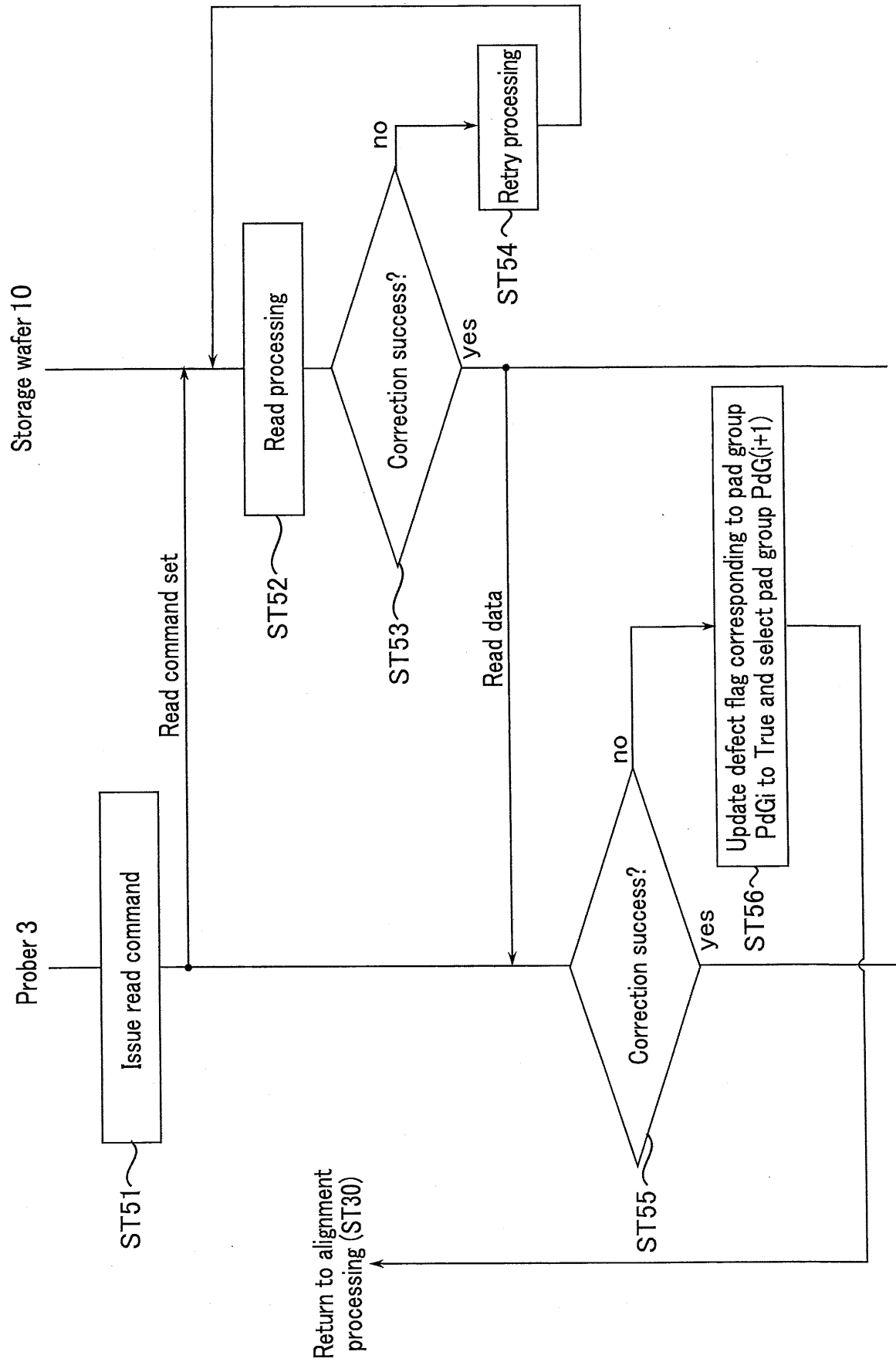


FIG. 20

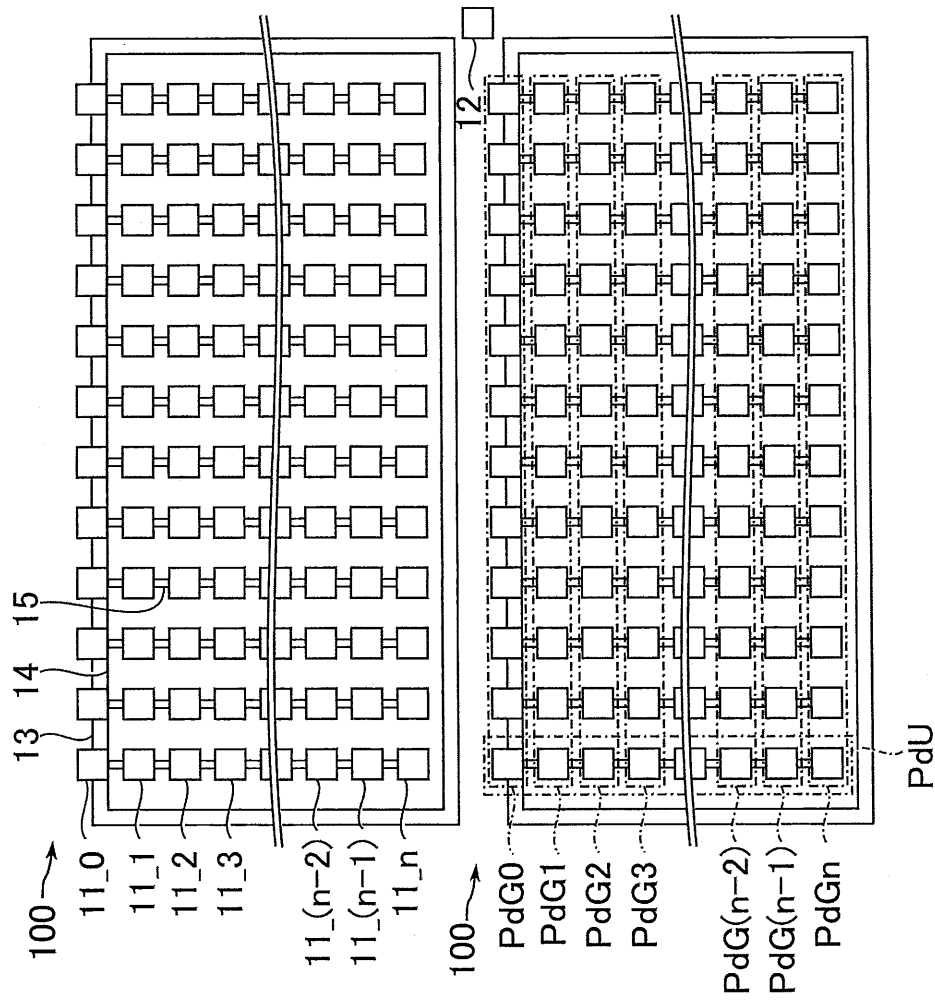


FIG. 21

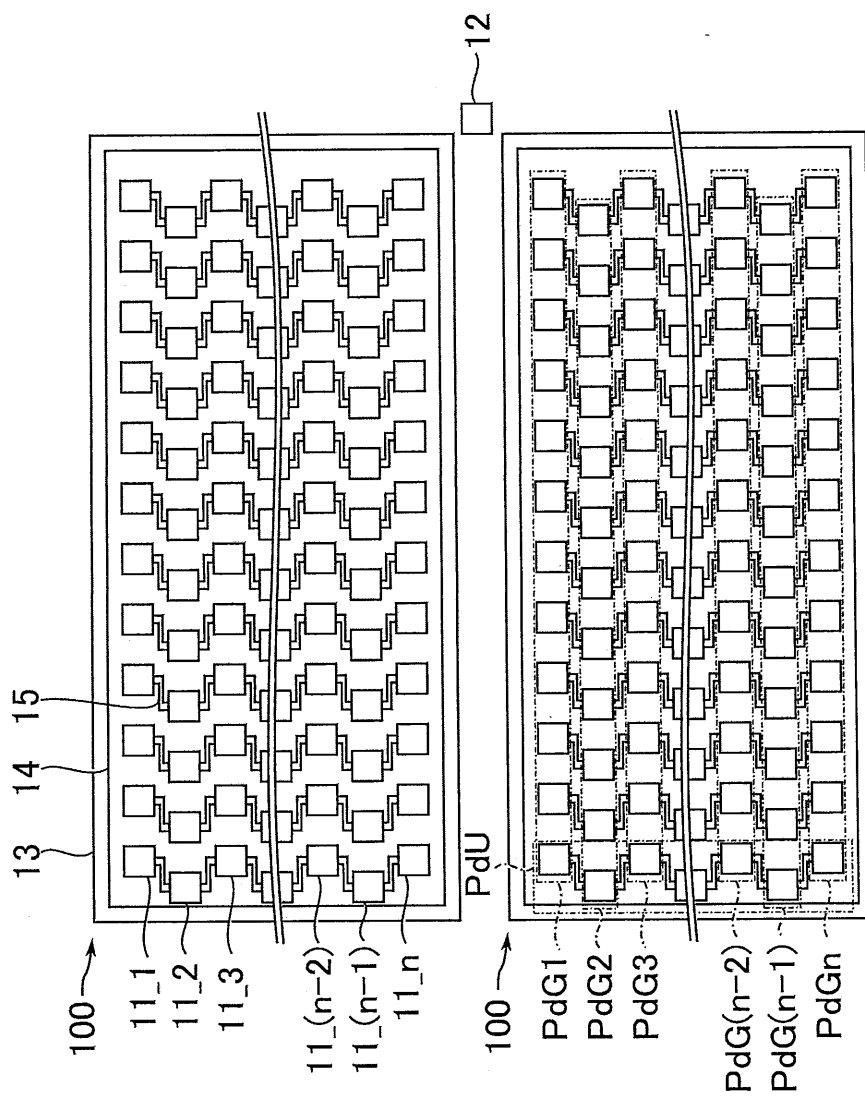


FIG. 22

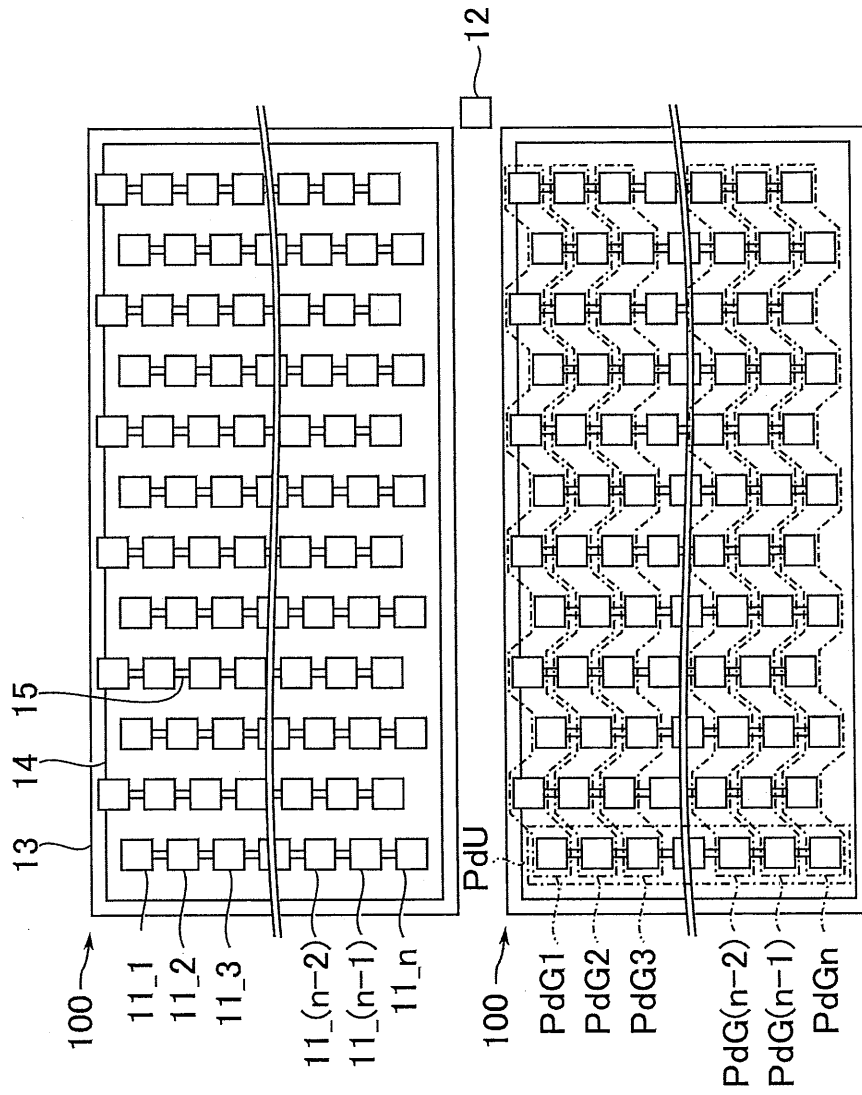


FIG. 23

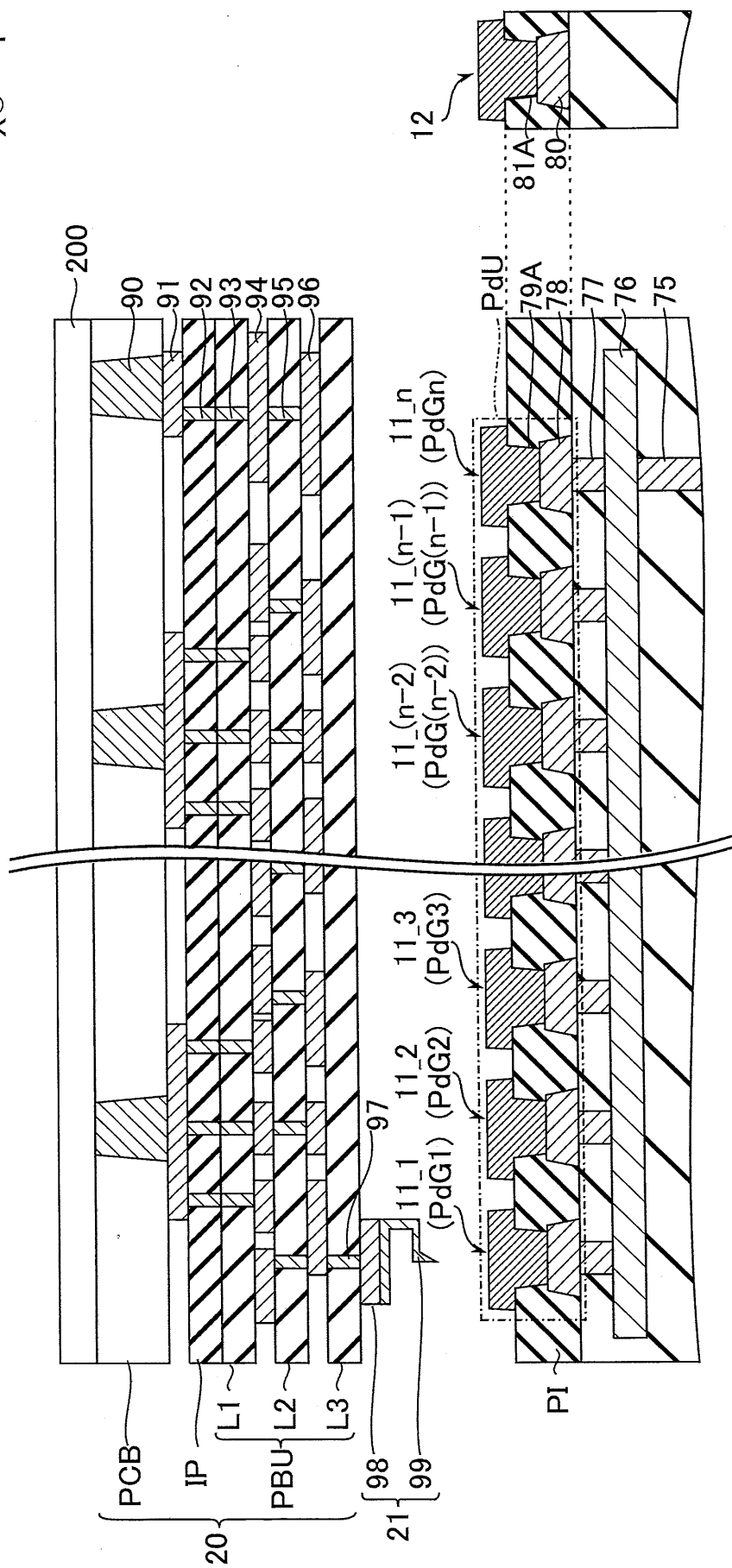
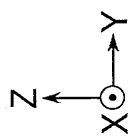


FIG. 24

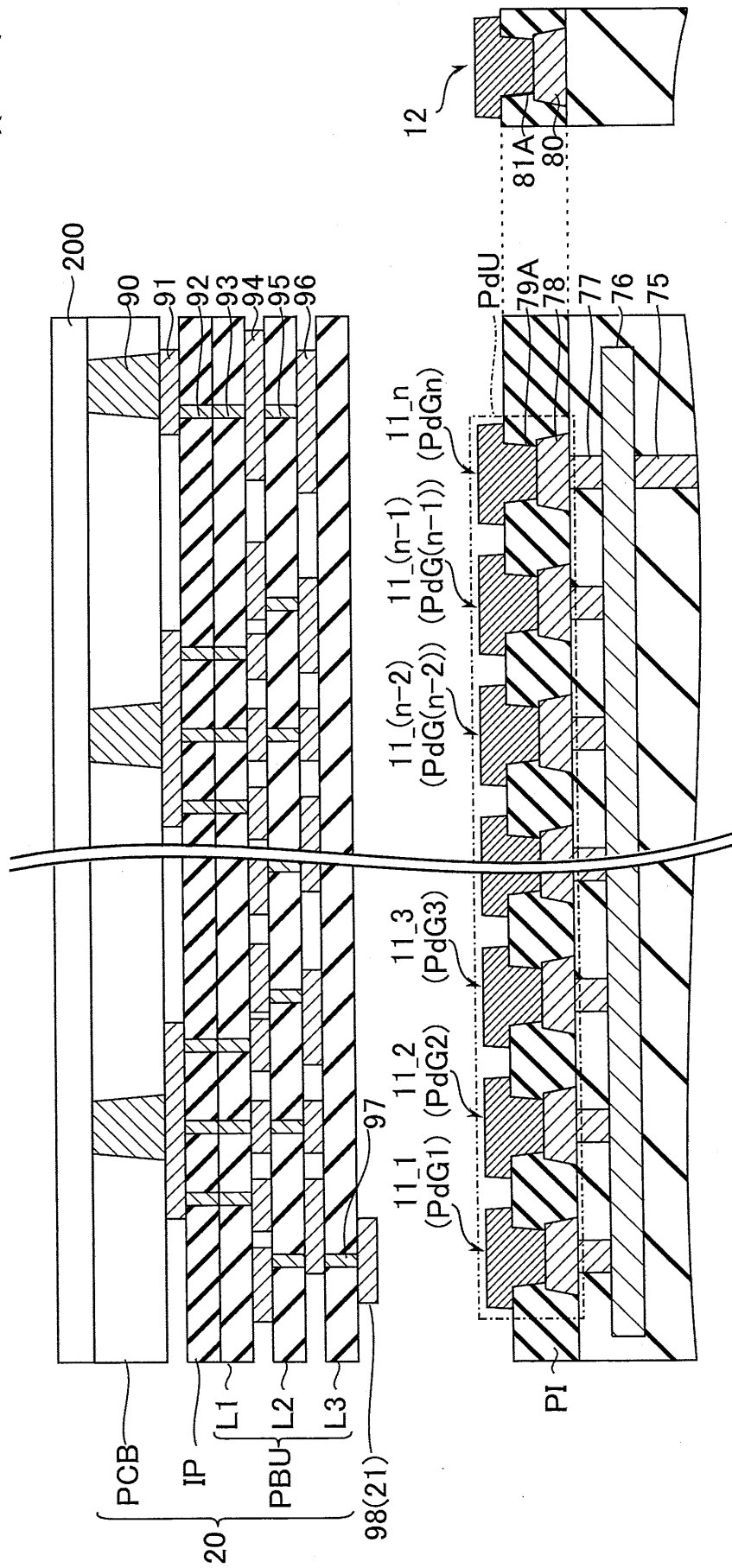
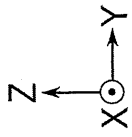


FIG. 25

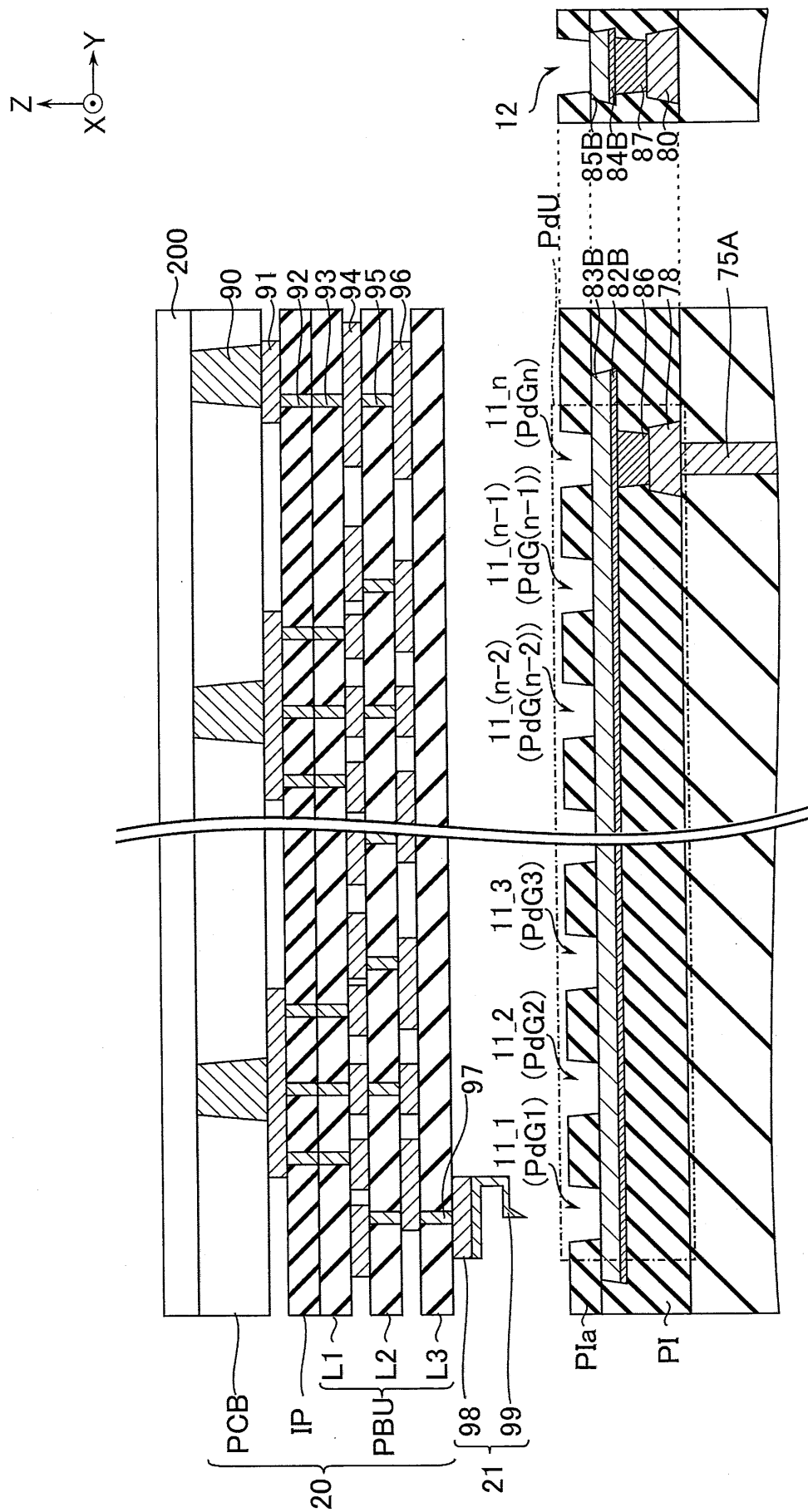


FIG. 28

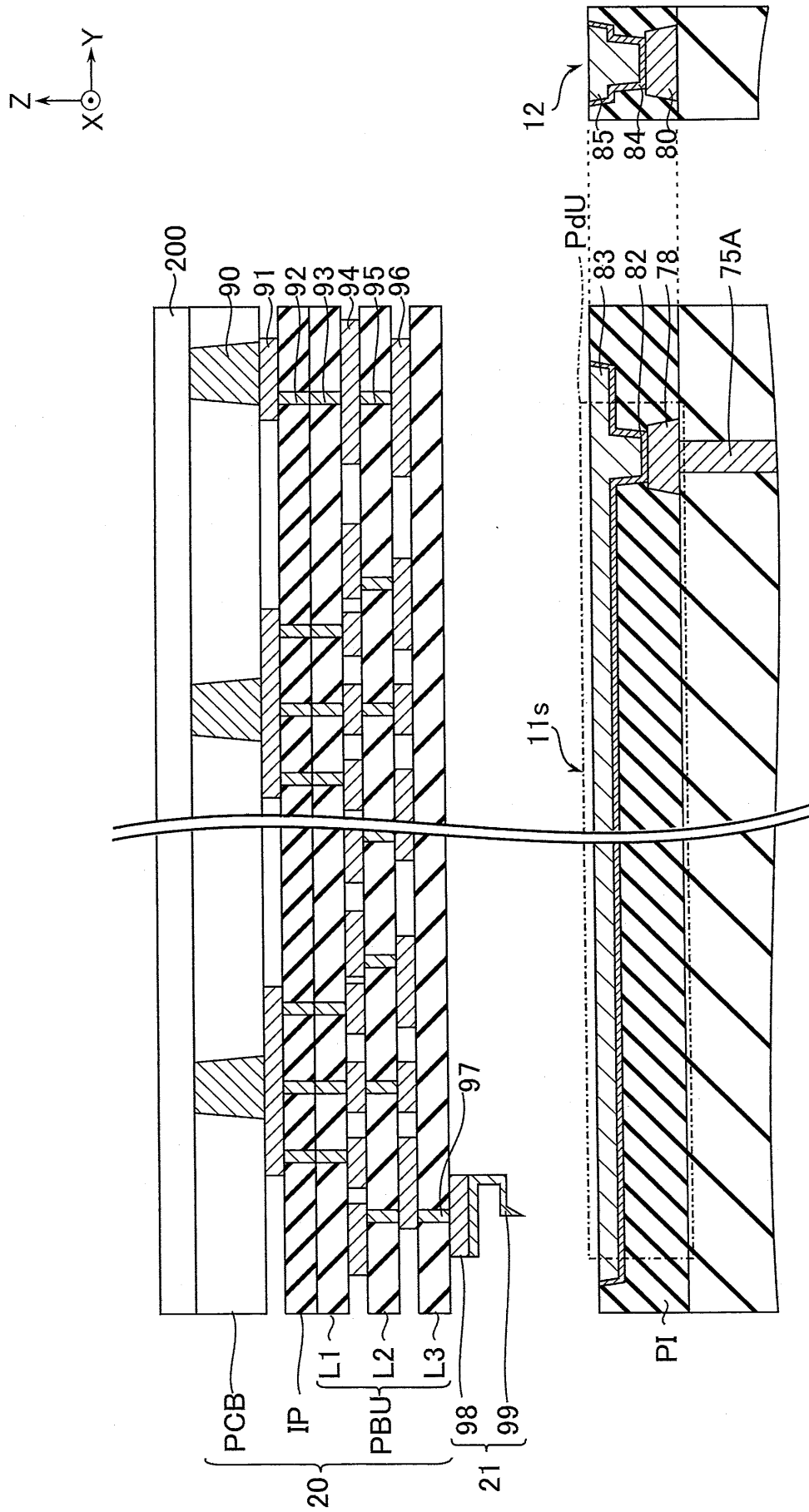


FIG. 29

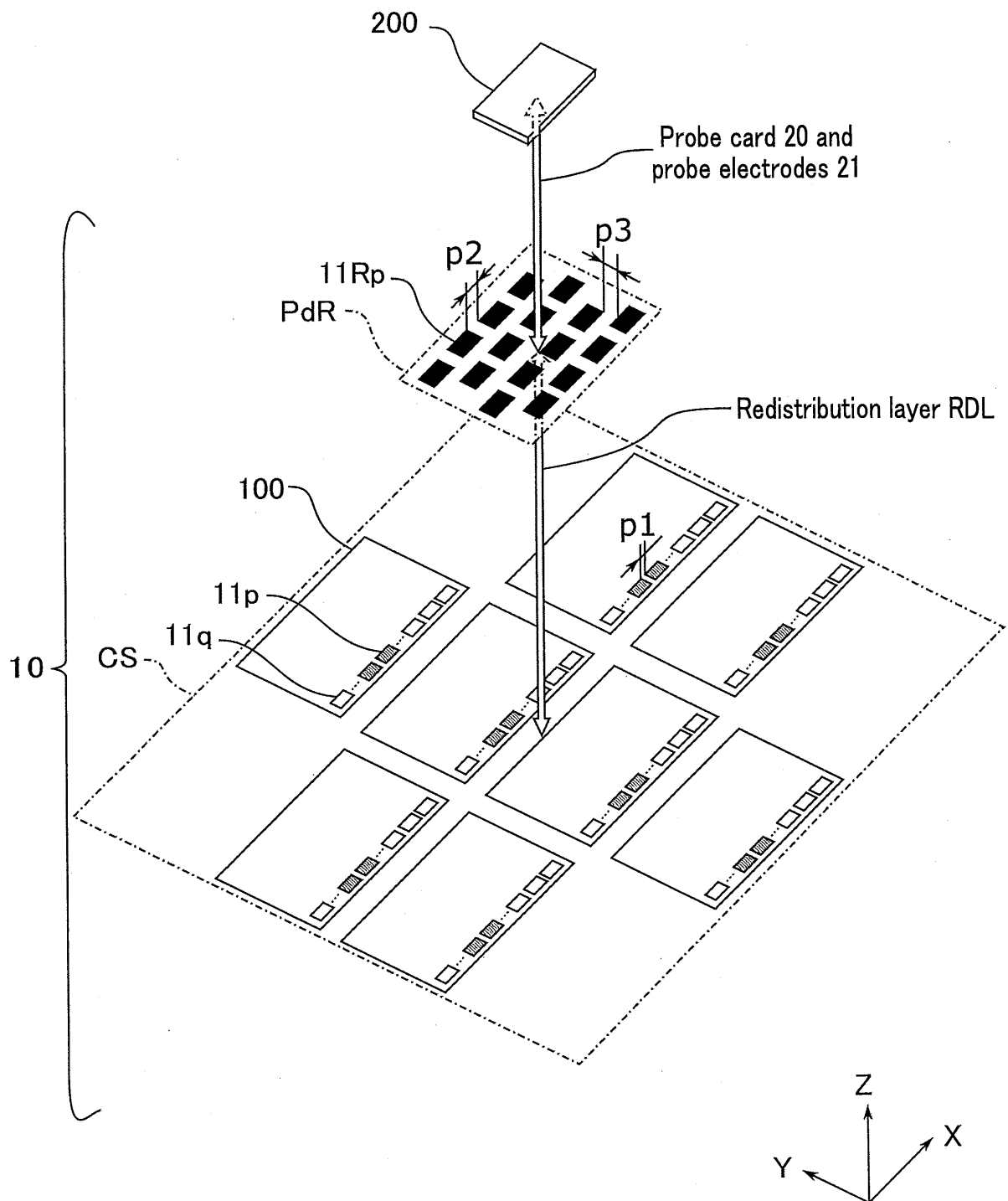


FIG. 30

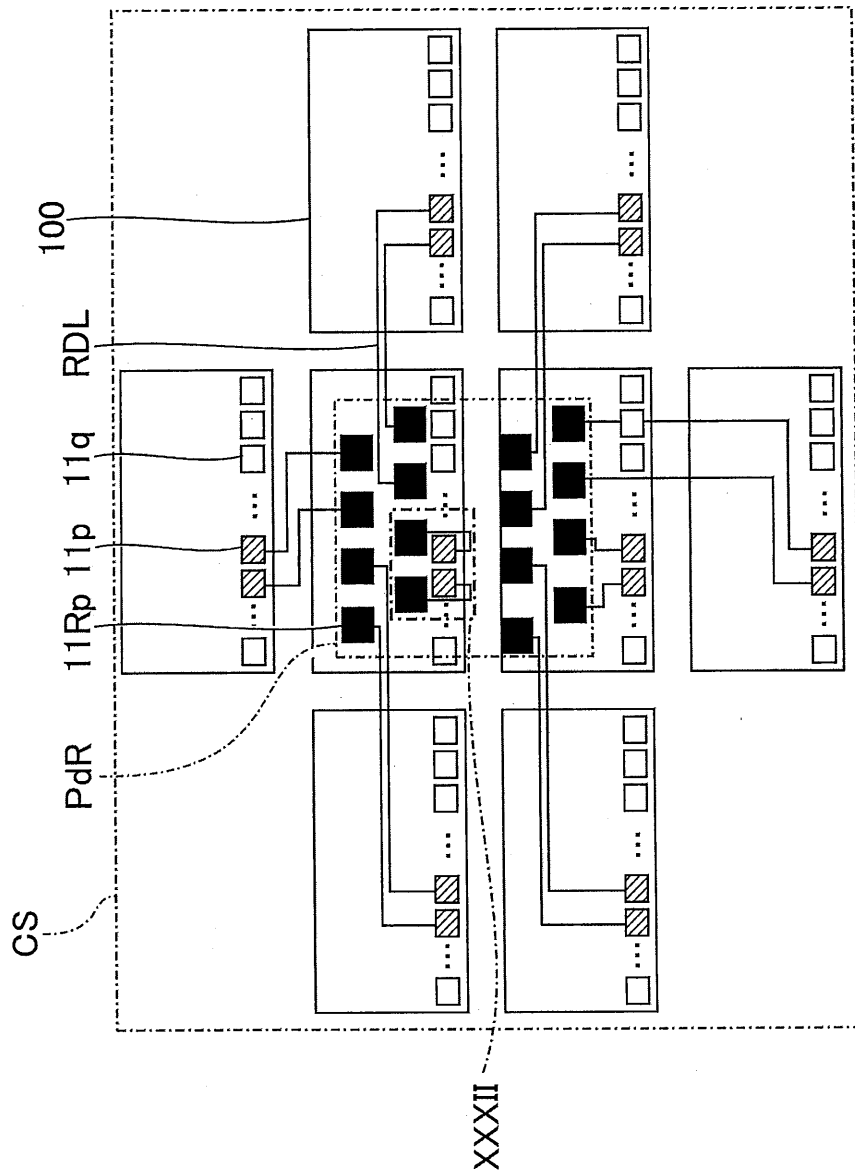


FIG. 31

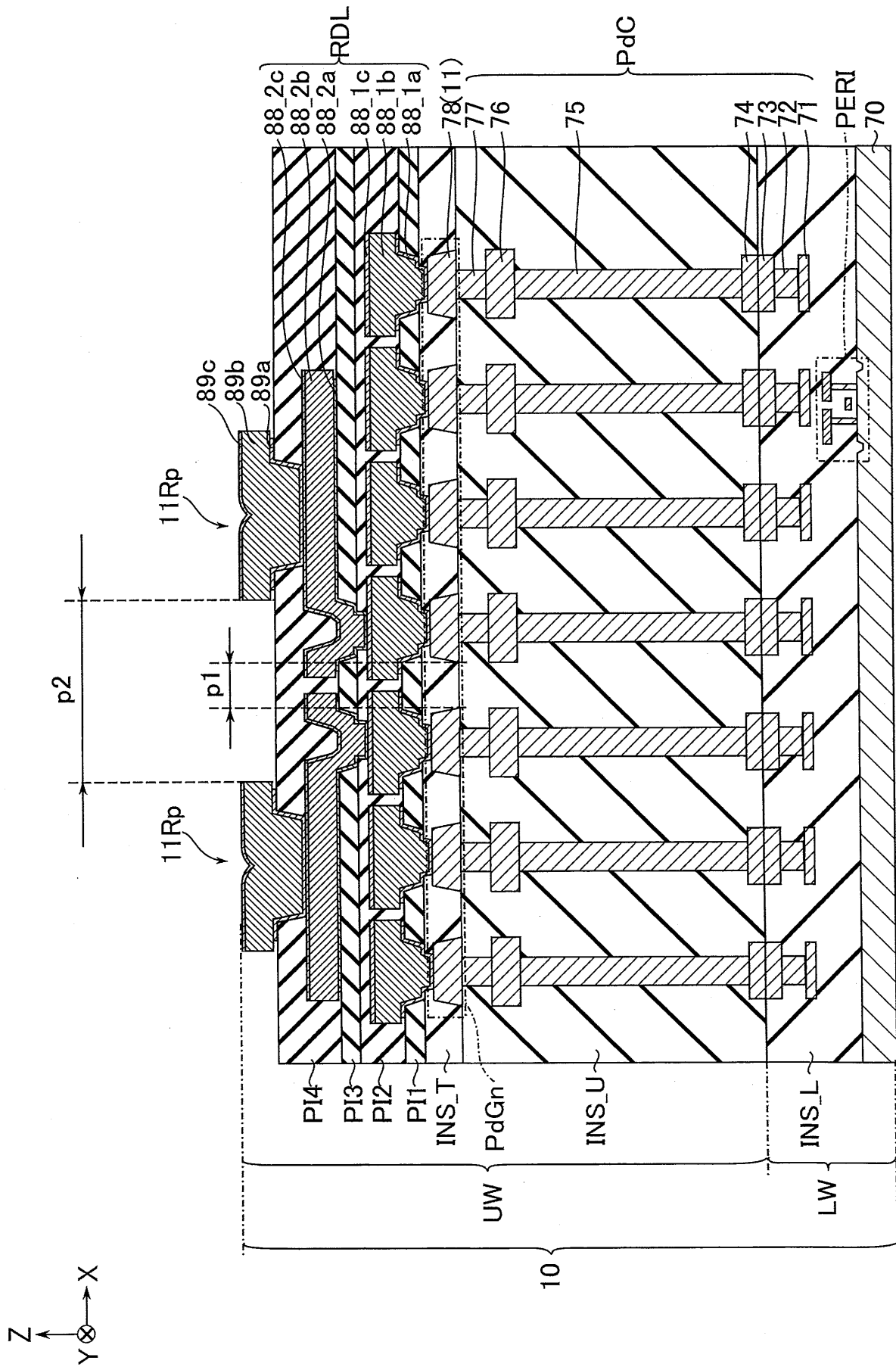


FIG. 32

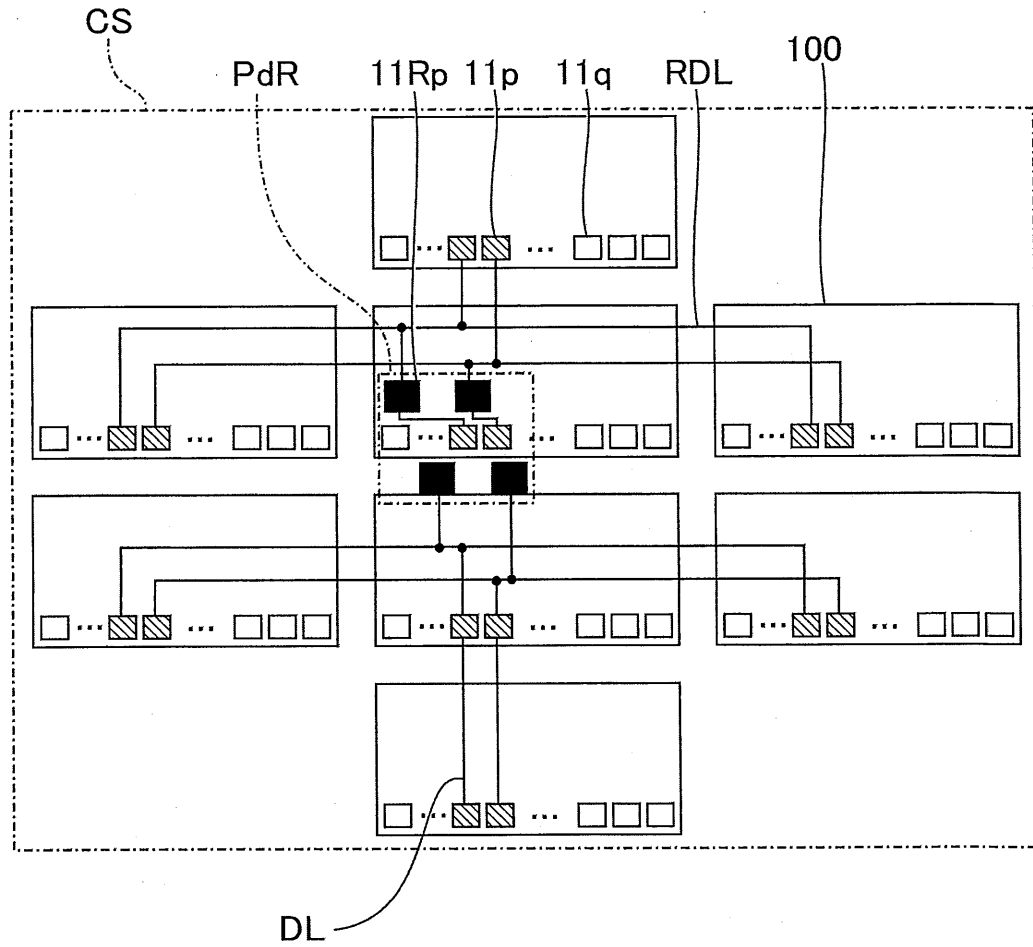


FIG. 33

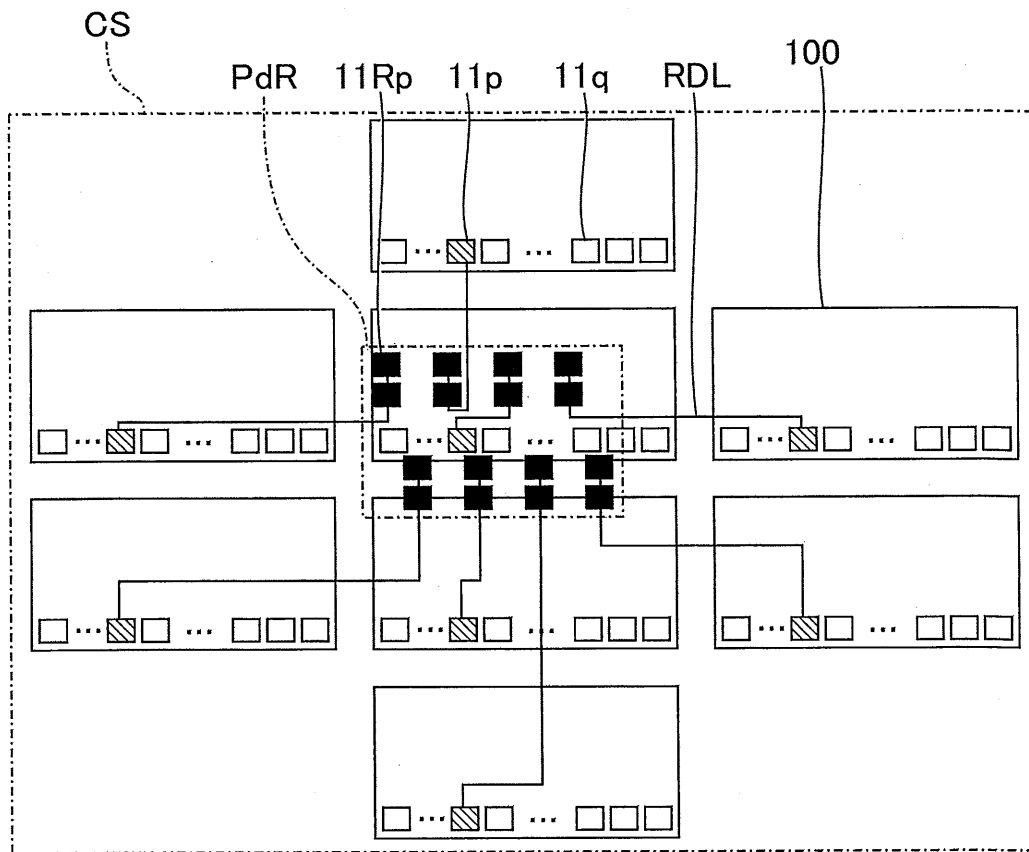


FIG. 34